## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | WU, DAVID CHAOHUA | Examiner | Art Unit | Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-2003/0162517	08-2003	Wu, David Chaohua	455/237.1
Х	В	US-6,295,362	09-2001	Zhang, Qin	381/2
X	С	US-6,259,482	07-2001	Easley et al.	348/485
Х	D	US-6,281,813	08-2001	Vierthaler et al.	341/50
Х	E	US-6,037,993	03-2000	Easley, Matthew Frank	348/485
Х	F	US-6,122,380	09-2000	Pedlow, Jr., Leo Mark	381/2
Х	G	US-6,492,913	12-2002	Vierthaler et al.	341/50
X	Н	US-6,664,849	12-2003	Taura et al.	329/315
Х	ı	US-2003/0091194	05-2003	Teichmann et al.	381/2
Х	J	US-6,535,608	03-2003	Taira, Masaaki	381/2
X	К	US-6,552,753	04-2003	Zhurbinskiy et al.	348/738
Х	L	US-6,118,879	09-2000	Hanna, Christopher M.	381/106
X	М	US-6,608,902	08-2003	Jackson et al.	381/1

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
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	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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